



4/20/2008

**RELIABILITY MONITOR REPORT  
FOR**

**DAL B8 Silicon Gate CMOS**

**MAXIM Integrated Products**

**120 San Gabriel Dr.  
Sunnyvale, CA 94086**

**This Report was prepared by  
Maxim Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS2413	DS8007	DS8113
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The calculated failure rate for devices using this process is:

**FAILURE RATE:**                      **MTTF (YRS): 15863**                      **FITS: 7.2**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2007 and 3/31/2008 .

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**Process Information:**

Process Description:              DAL B8 Silicon Gate CMOS

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	FA NO
HIGH TEMP OP LIFE	0713	DS2413	125C, 5.25 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0724	DS8007	125C, 6.0 VOLTS	1000 HRS	45	0	
HIGH TEMP OP LIFE	0744	DS8113	125C, 6.0 VOLTS	1000 HRS	45	0	
				<b>Total:</b>		<b>0</b>	

**FAILURE RATE:**                      **MTTF (YRS): 15863**                      **FITS: 7.2**